

### General Description

The MY040FNC uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

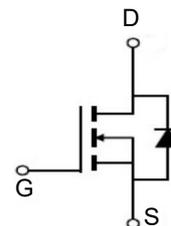
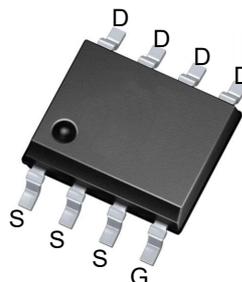


: YUhi fYg

$V_{DS}$	60	X
$V_{GS}$	6.5	C
$T_{FUTOP} @ V_{GS} = 10V$	>37	o á
$T_{FUTOP} @ V_{GS} = 4.5V$	>48	o á

### Application

- Battery protection
- 5V regulator
- Motor driver



### DUW U[ Y A Uf ]b[ UbX CfXYf]b[ -bZfa U]cb

DfcXi Wi-8	DUW	A Uf ]b[	E ImfD7 GŁ
MY040FNC	ÙÚÚË	040FNC	HEEE

5 Vgc`i hY'AU ja i a 'FU]b[ g'fH,1&) °C unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	60	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_{D@T_A=25^\circ C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	6.5	A
$I_{D@T_A=70^\circ C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	5.5	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	18	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	22	mJ
$I_{AS}$	Avalanche Current	21	A
$P_D@T_A=25^\circ C$	Total Power Dissipation <sup>4</sup>	1.5	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C
$R_{\theta JA}$	Thermal Resistance Junction-ambient <sup>1</sup>	85	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	25	°C/W

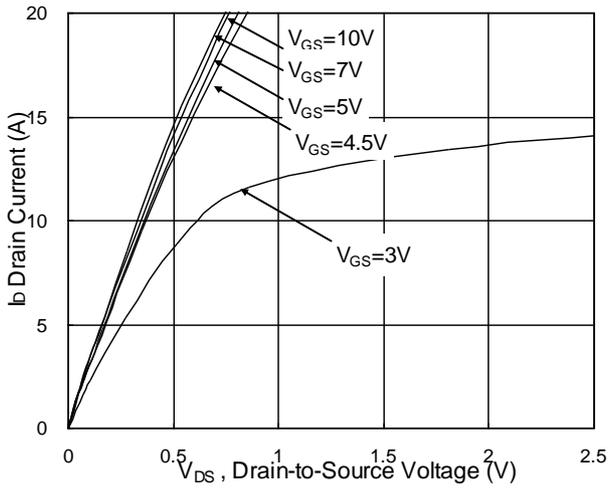
**Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	60	---	---	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	BVDSS Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA	---	0.044	---	V/°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =4A	---	28	37	mΩ
		V <sub>GS</sub> =4.5V , I <sub>D</sub> =2A	---	35	48	
V <sub>GS(th)</sub>	Gate Threshold Voltage		1.0	1.6	2.5	V
ΔV <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	---	-4.8	---	mV/°C
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =48V , V <sub>GS</sub> =0V , T <sub>J</sub> =25 °C	---	---	1	uA
		V <sub>DS</sub> =48V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C	---	---	5	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = ±20V , V <sub>DS</sub> =0V	---	---	±100	nA
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =4A	---	28.3	---	S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz	---	2.5	---	
Q <sub>g</sub>	Total Gate Charge (10V)	V <sub>DS</sub> =48V , V <sub>GS</sub> =10V , I <sub>D</sub> =4A	---	19	---	nC
Q <sub>gs</sub>	Gate-Source Charge		---	2.6	---	
Q <sub>gd</sub>	Gate-Drain Charge		---	4.1	---	
T <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> =30V , V <sub>GS</sub> =10V , R <sub>G</sub> =3.3 I <sub>D</sub> =4A	---	3	---	ns
T <sub>r</sub>	Rise Time		---	34	---	
T <sub>d(off)</sub>	Turn-Off Delay Time		---	23	---	
T <sub>f</sub>	Fall Time		---	6	---	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz	---	1027	---	pF
C <sub>oss</sub>	Output Capacitance		---	65	---	
C <sub>rss</sub>	Reverse Transfer Capacitance		---	46	---	
I <sub>S</sub>	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current	---	---	4.5	A
I <sub>SM</sub>	Pulsed Source Current <sup>2,5</sup>		---	---	18	A
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C	---	---	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> =4A, dI/dt=100A/μs,	---	12.1	---	nS
Q <sub>rr</sub>	Reverse Recovery Charge		---	6.7	---	nC

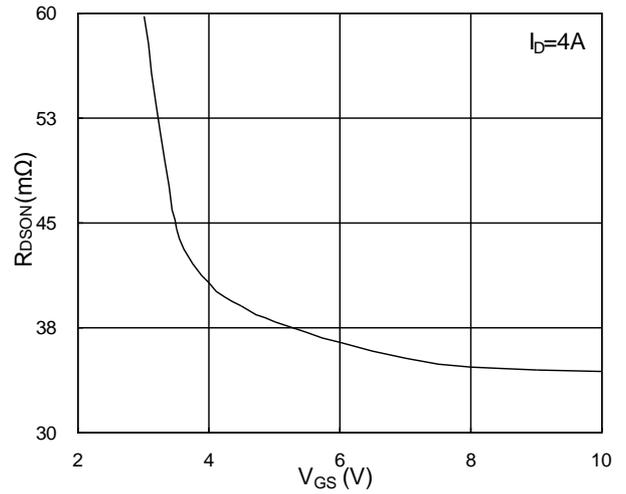
Note :

- 1 .The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3 .The EAS data shows Max. rating . The test condition is V<sub>DD</sub>=25V, V<sub>GS</sub>=10V, L=0.1mH, I<sub>AS</sub>=21A
- 4.The power dissipation is limited by 150°C junction temperature 5 .The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub> , in real applications , should be limited by total power dissipation.

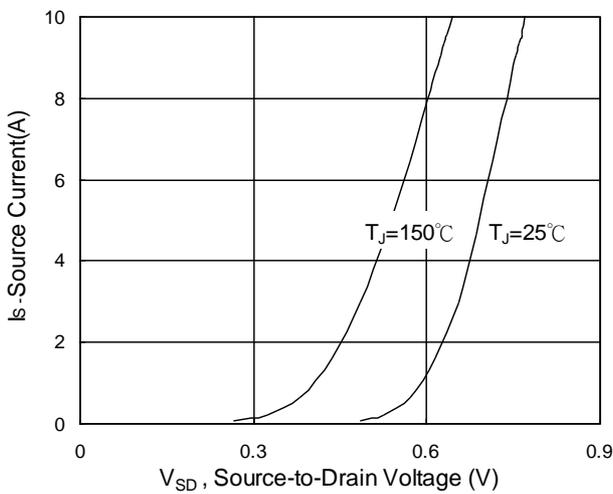
**Typical Characteristics**



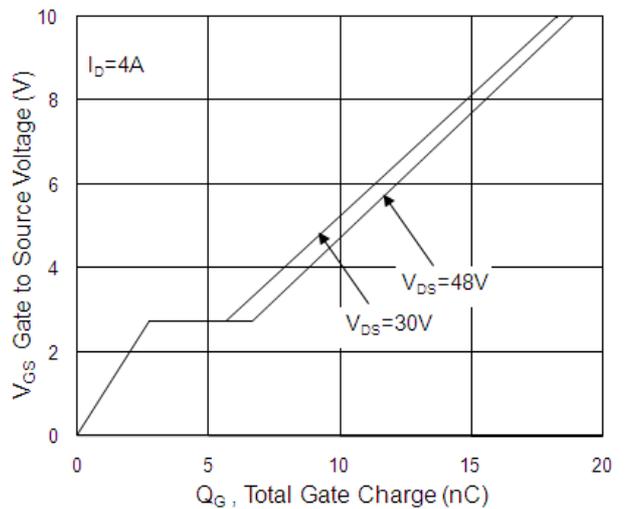
**Fig.1 Typical Output Characteristics**



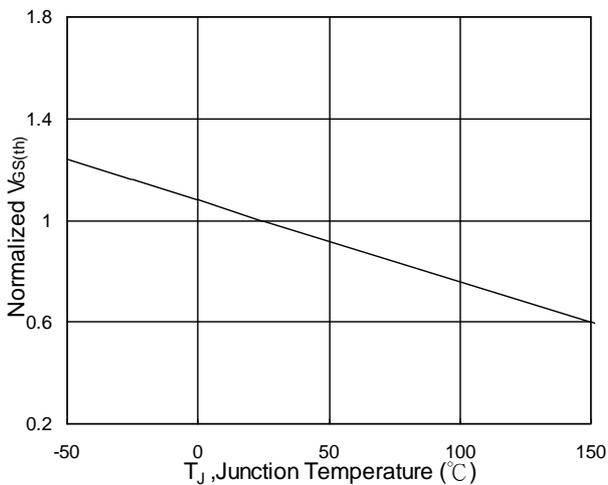
**Fig.2 On-Resistance vs. Gate-Source**



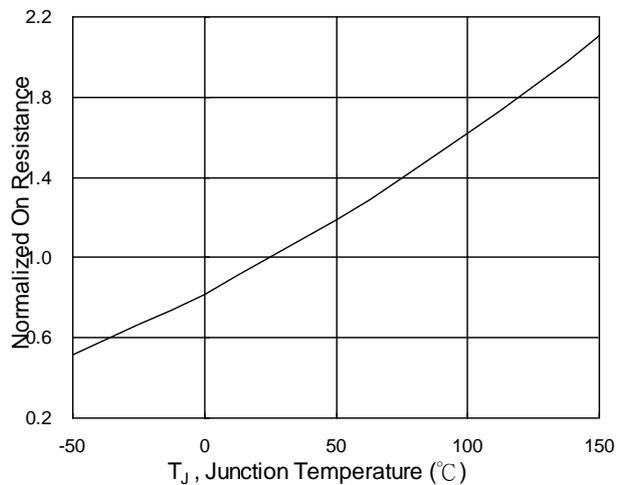
**Fig.3 Forward Characteristics Of Reverse**



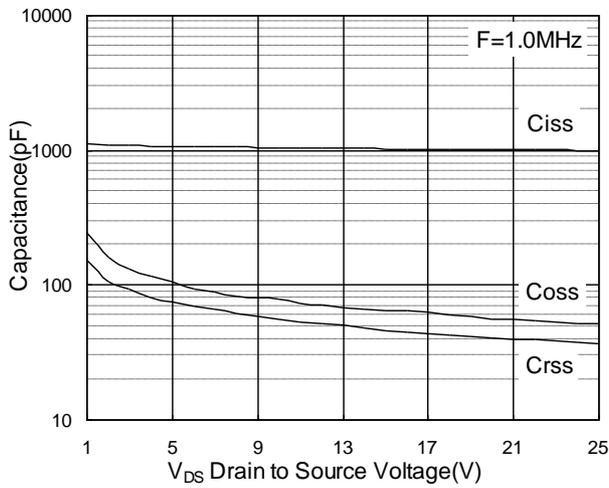
**Fig.4 Gate-Charge Characteristics**



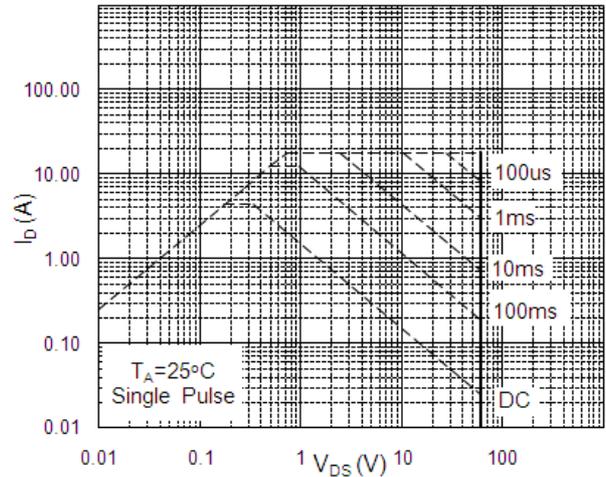
**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$**



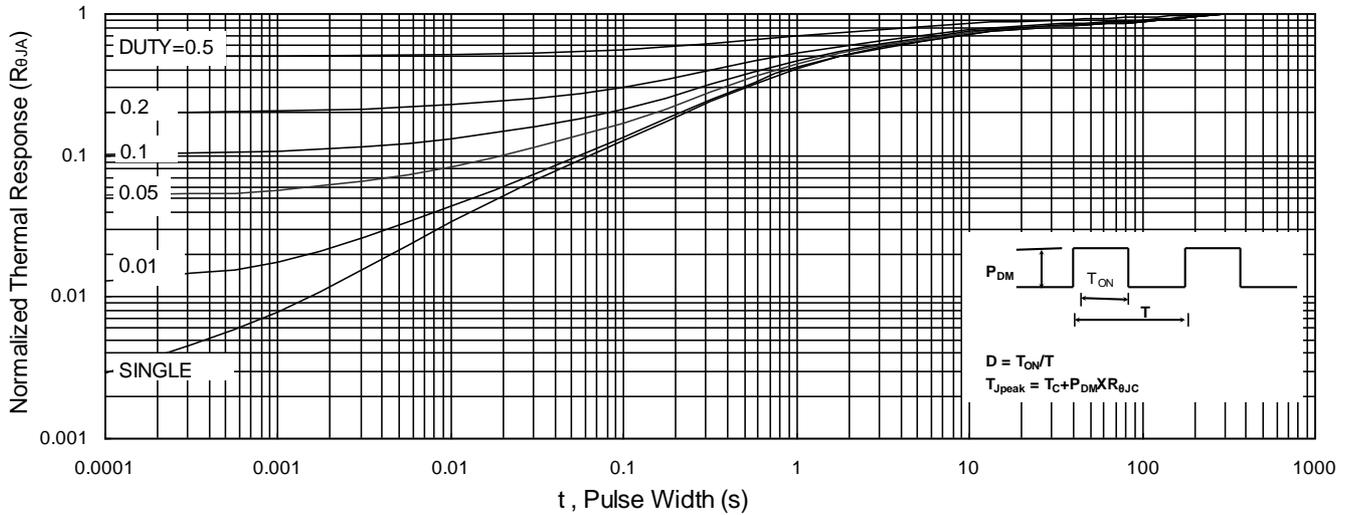
**Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$**



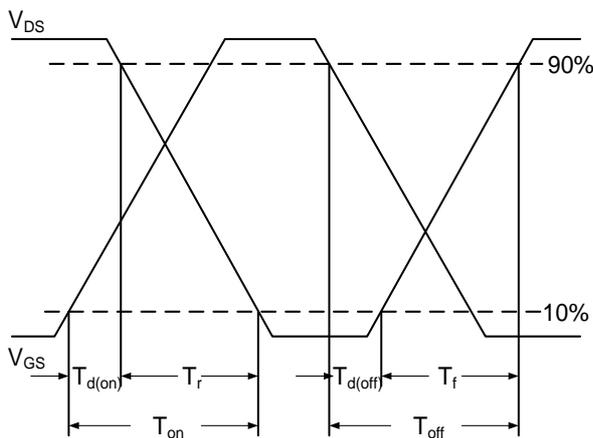
**Fig.7 Capacitance**



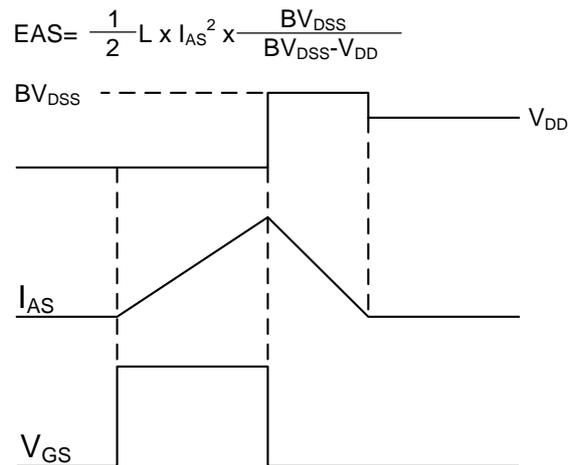
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**



**Fig.10 Switching Time Waveform**



**Fig.11 Unclamped Inductive Switching Waveform**

**Package Mechanical Data-SOP-8**

